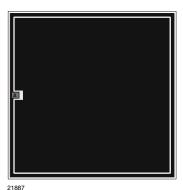


Vishay Semiconductors

Silicon PIN Photodiode



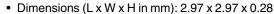
DESCRIPTION

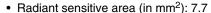
T1116P is a PIN photodiode with blue enhanced sensitivity and a 7.7 mm² sensitive area.

FEATURES

• Package type: chip







· High photo sensitivity

· High radiant sensitivity

- · Suitable for visible and near infrared radiation
- · Fast response times
- Angle of half sensitivity: $\varphi = \pm 60^{\circ}$
- Compliant to RoHS directive 2002/95/EC and in accordance to WEEE 2002/96/EC



· Blue enhanced photodetectors

GENERAL INFORMATION

The datasheet is based on Vishay optoelectronics sample testing under certain predetermined and assumed conditions, and is provided for illustration purpose only. Customers are encouraged to perform testing in actual proposed packaged and used conditions. Vishay optoelectronics die products are tested using Vishay optoelectronics based quality assurance procedures and are manufactured using Vishay optoelectronics established processes. Estimates such as those described and set forth in this datasheet for semiconductor die will vary depending on a number of packaging, handling, use, and other factors. Therefore sold die may not perform on an equivalent basis to standard package products.

PRODUCT SUMMARY				
COMPONENT	I _{ra} (μΑ)	φ (deg)	λ _{0.1} (nm)	
T1116P	43	± 60	350 to 1100	

Note

Test conditions see table "Basic Characteristics"

ORDERING INFORMATION					
ORDERING CODE	PACKAGING	REMARKS	PACKAGE FORM		
T1116P-SD-F	Wafer sawn on foil with disco frame	MOQ: 1500 pcs	Chip		

Note

MOQ: minimum order quantity

ABSOLUTE MAXIMUM RATINGS					
PARAMETER	TEST CONDITION	SYMBOL	VALUE	UNIT	
Reverse voltage		V _R	25	V	
Junction temperature		Tj	100	°C	
Operating temperature range		T _{amb}	- 40 to + 100	°C	
Storage temperature range		T _{stg1}	- 40 to + 100	°C	
Storage temperature range on foil		T _{stq2}	- 40 to + 50	°C	

Note

T_{amb} = 25 °C, unless otherwise specified

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BASIC CHARACTERISTICS (1)						
PARAMETER	TEST CONDITION	SYMBOL MIN. TYP.		MAX.	UNIT	
Breakdown voltage	I _R = 100 μA, E = 0	V _(BR) 25				V
Forward voltage	I _F = 50 mA V _F 1				1.3	V
Reverse dark current	V _R = 10 V, E = 0	= 0 I _{ro} 2 5				nA
Diodo consoitanos	V _R = 0 V, f = 1 MHz, E = 0 C _D			90		pF
Diode capacitance	V _R = 3 V, f = 1 MHz, E = 0	V _R = 3 V, f = 1 MHz, E = 0 C _D		30		pF
Temperature coefficient of I _{ra}	$E_e = 1 \text{ mW/cm}^2, \lambda = 950 \text{ nm}$	= 950 nm TK _{IK} 0.1			%/K	
Reverse light current	$E_e = 1 \text{ mW/cm}^2, \ \lambda = 950 \text{ nm}, \ V_R = 5 \text{ V}$	I _{ra}	I _{ra} 43			μА
	$E_e = 1 \text{ mW/cm}^2, \ \lambda = 400 \text{ nm}, \\ V_R = 5 \text{ V}$	I _{ro}		13		μΑ
	$E_V = 100 \text{ lx},$ CIE illuminant A, $V_R = 5 \text{ V}$	I _{ro}		7.1		μΑ
Angle of half sensitivity		φ		± 60		deg
Wavelength of peak sensitivity		λ_{p}		940		nm
Range of spectral bandwidth		λ _{0.1}		350 to 1100		nm
Noise equivalent power	$V_R = 10 \text{ V}, \lambda = 400 \text{ nm}$	NEP		1.1 x 10 ⁻¹³		W/√Hz
Rise time	$V_R = 5 \text{ V}, R_L = 500 \Omega,$ $\lambda = 850 \text{ nm}$	t _r 40			ns	
Fall time	$V_R = 10 \text{ V}, R_L = 1 \text{ k}\Omega,$ $\lambda = 820 \text{ nm}$	t _f 40			ns	

Notes

BASIC CHARACTERISTICS

T_{amb} = 25 °C, unless otherwise specified

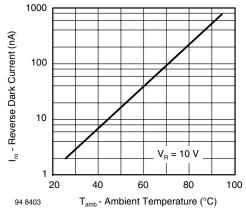


Fig. 1 - Reverse Dark Current vs. Ambient Temperature

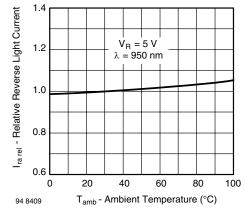


Fig. 2 - Relative Reverse Light Current vs. Ambient Temperature

 $^{^{(1)}}$ T_{amb} = 25 °C, unless otherwise specified

⁽²⁾ The measurements are based on samples of die which are mounted on a TO-header without resin coating



Silicon PIN Photodiode

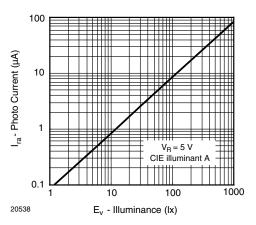


Fig. 3 - Photo Current vs. Illuminance

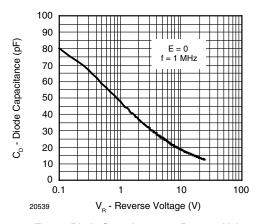


Fig. 4 - Diode Capacitance vs. Reverse Voltage

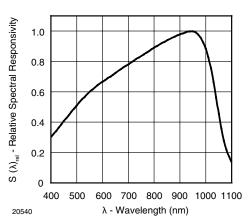


Fig. 5 - Relative Spectral Sensitivity vs. Wavelength

MECHANICAL DIMENSIONS					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Length of chip edge (x-direction)	L _x		2.97		mm
Length of chip edge (y-direction)	L _y		2.97		mm
Sensitive area	As		2.77 x 2.77		mm ²
Die height	Н		0.28		mm
Bond pad anode	axb		0.125 x 0.110		mm ²

ADDITIONAL INFORMATION (1)				
Frontside metallization, anode	Aluminum			
Backside metallization, cathode	NiV-Ag			
Dicing	Sawing			
Die bonding technology	Epoxy bonding			

Note

The quality inspection (final visual inspection) is performed by production. An additional visual inspection step as special release procedure by QM is not installed.

⁽¹⁾ All chips are checked in accordance with the Vishay Semiconductor, specification of visual inspection FVOV6870.

The visual inspection shall be made in accordance with the "specification of visual inspection as referenced". The visual inspection of chip backside is performed with stereo microscope with incident light and 40x to 80x magnification.

T1116P

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HANDLING AND STORAGE CONDITIONS

- The hermetically sealed shipment lots shall be opened in temperature and moisture controlled cleanroom environment only. It is mandatory to follow the rules for disposition of material that can be hazardous for humans and environment.
- Product must be handled only at ESD safe workstations. Standard ESD precautions and safe work environments are as defined in MIL-HDBK-263.
- Singulated die are not to be handled with tweezers. A vacuum wand with non metallic ESD protected tip should be used.

PACKING

Chips are fixed on adhesive foil. Upon request the foils can be mounted on plastic frame or disco frame. For shipment, the wafers are arranged to stacks and hermetically sealed in plastic bags to ensure protection against environmental influence (humidity and contamination).

Use for recycling reliable operators only. We can help getting in touch with your nearest sales office. By agreement we will take back packing material, if it is sorted. You will have to bear the costs of transport. We will invoice you for any costs incurred for packing material that is returned unsorted or which we are not obliged to accept.





Vishay

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